In the Claims:

1. A method of measuring jitter in a device under test comprising the steps of:
providing a coherent sample signal to the device under test;
unwrapping the data from the device;
performing FFT of the unwrapped data;
removing the DC harmonic and the fundamental from the FFT of the unwrapped data;
performing an inverse FFT of the FFT of the unwrapped data with the DC harmonic and fundamental removed to get code error;
adjusting the code error to a predetermined phase;
determining the variance of the code error at the low slew rate;
determining the variance of the code error at the high slew rate;
calculating the jitter on each angle from the high slew variance by each angle and the low slew rate variance.

2. The method of claim 1 wherein said method includes the step of removing sparkle codes before adjusting the phase code error.

3. The method of claim 2 including the step of averaging the jitter for all angles that the jitter is calculated.

4. The method of claim 1 including the step of averaging the jitter for all angles that the jitter is calculated.